



Product data sheet

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SI2302CDS-T1-GE3-MS

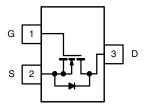
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Features

- 20V, 3A, RDS(ON) =40mΩ@VGS = 4.5V
- Improved dv/dt capability
- Fast switching
- Green Device Available

SOT-23



Applications

- Notebook
- Load Switch
- Hend-Held Instruments

BVDSS	RDSON	ID
20V	$40 \text{m}\Omega$	3A

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	20	V
V _{GS}	Gate-Source Voltage	±12	V
I	Drain Current – Continuous (T _c =25°C)	3	A
ID	Drain Current – Continuous (Tc=100°C)	2	A
Ы	Drain Current – Pulsed ¹	16	A
	Power Dissipation (T _c =25°C)	1.56	W
P _D	Power Dissipation – Derate above 25°C	0.012	W/°C
Г _{STG}	Storage Temperature Range	-55 to 150	°C
ГJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
R _{0JA}	A Thermal Resistance Junction to ambient		80	°C/W



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Electrical Characteristics (TJ=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions		Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage V _{GS} =0V , I _D =250uA		20			V
$\triangle BV_{DSS} / \triangle T_{J}$	J BV _{DSS} Temperature Coefficient Reference to 25°C , I _D =1mA			0.02		V/°C
	Drain Source Leekers Current	V _{DS} =20V , V _{GS} =0V , T _J =25°C			1	uA
I _{DSS} Drain-Source Leakage Current	Drain-Source Leakage Current	V _{DS} =16V , V _{GS} =0V , T _J =125°C			10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±12V , V _{DS} =0V			±100	nA

On Characteristics

R _{DS(ON)} Static Drain-Source On-Resistance	Statia Duain Source On Desistance	V _{GS} =4.5V , I _D =2A		40	55	mΩ
	V _{GS} =2.5V , I _D =1A		55	75	1115.2	
V _{GS(th)}	Gate Threshold Voltage		0.4	0.5	1	V
∆V _{GS(th)}	V _{GS(th)} Temperature Coefficient	────V _{GS} =V _{DS} , I _D =250uA		2		mV/°C
gfs	Forward Transconductance	V _{DS} =10V , I _S =2A		4.4		S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2 , 3}			3.6	
Q _{gs}	Gate-Source Charge ^{2,3}	V _{DS} =10V , V _{GS} =4.5V , I _D =1A		0.38	 nC
Q _{gd}	Gate-Drain Charge ^{2,3}			0.6	
T _{d(on)}	Turn-On Delay Time ^{2 , 3}			1.8	
Tr	Rise Time ^{2 , 3}	V_{DD} =10V , V_{GS} =4.5V , R_{G} =25 Ω I _D =1A		5.6	 nS
T _{d(off)}	Turn-Off Delay Time ^{2 , 3}			11.3	 115
T _f	Fall Time ^{2 , 3}			3.2	
C _{iss}	Input Capacitance			180	
C _{oss}	Output Capacitance	V _{DS} =15V , V _{GS} =0V , F=1MHz		32	 pF
C _{rss}	Reverse Transfer Capacitance			26	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions		Тур.	Max.	Unit
ls	Continuous Source Current	V =V =0V Force Current			3	А
I _{SM}	Pulsed Source Current	V _G =V _D =0V , Force Current			6	А
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =1A , T _J =25°C			1.2	V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.

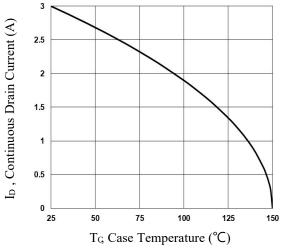
2. The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%.$

3. Essentially independent of operating temperature.

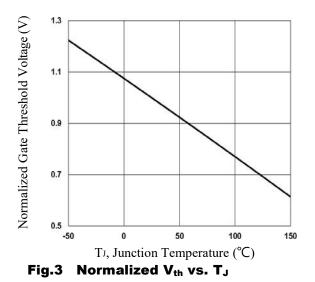


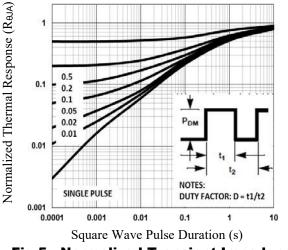
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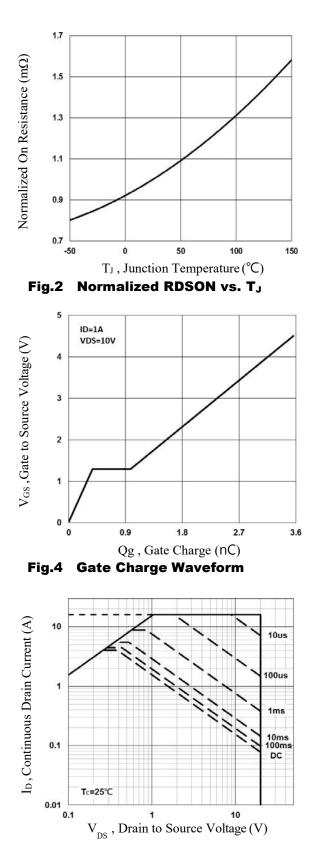








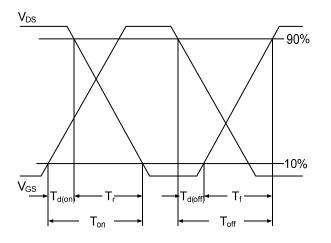






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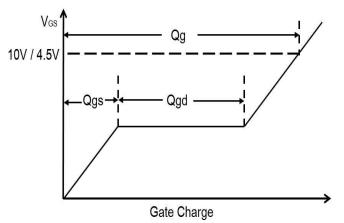


Fig.7 Switching Time Waveform

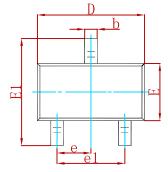
Fig.8 Gate Charge Waveform

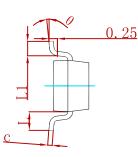


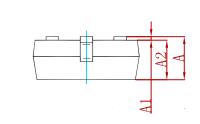
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PACKAGE MECHANICAL DATA

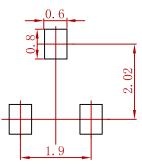






Cumph of	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
А	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
с	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950) TYP	0.03	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	2 REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.

3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SI2302CDS-T1-GE3-MS	SOT-23	3000



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